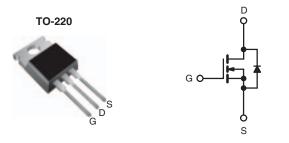


Vishay Siliconix

Power MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	600			
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = 10 V	0.35		
Q _g (Max.) (nC)	99			
Q _{gs} (nC)	32			
Q _{gd} (nC)	47			
Configuration	Single			



N-Channel MOSFET

FEATURES

- Smaller TO-220 Package
- ullet Low Gate Charge ${\bf Q}_{\bf g}$ Results in Simple Drive Requirement



- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche Voltage and Current
- Lead (Pb)-free Available

APPLICATIONS

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply
- · High Speed Power Switching
- · Hard Switched and High Frequency Circuits

TO-220
IRFB17N60KPbF
SiHFB17N60K-E3
IRFB17N60K
SiHFB17N60K

ABSOLUTE MAXIMUM RATINGS T	_C = 25 °C, u	nless otherw	ise noted			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V_{DS}	600	V	
Gate-Source Voltage			V_{GS}	± 30		
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C		17		
	VGS at 10 V	T _C = 100 °C	I _D	11	Α	
Pulsed Drain Current ^a			I _{DM}	68		
Linear Derating Factor				2.7	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	330	mJ	
Repetitive Avalanche Current ^a			I _{AR}	17	Α	
Repetitive Avalanche Energy ^a			E _{AR}	34	mJ	
Maximum Power Dissipation	T _C = 25 °C		P _D	340	W	
Peak Diode Recovery dV/dt ^c			dV/dt	11	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)	for 10 s			300 ^d		
Mounting Torque	6-32 or M3 screw			10	N	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Starting $T_J = 25$ °C, L = 2.3 mH, $R_G = 25$ Ω , $I_{AS} = 17$ A (see fig. 12).
- c. $I_{SD} \le 17$ A, $dI/dt \le 380$ A/ μ s, $V_{DD} \le V_{DS}$, $T_J \le 150$ °C.
- d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply

IRFB17N60K, SiHFB17N60K

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THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	58		
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.50	-	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	0.37		

PARAMETER	SYMBOL	TES	MIN.	TYP.	MAX.	UNIT	
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		600	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referen	Reference to 25 °C, I _D = 1 mA		600	-	mV/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} :	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$		-	5.0	V
Gate-Source Leakage	I _{GSS}		V _{GS} = ± 30 V		-	± 100	nA
Zero Gate Voltage Drain Current	l	V _{DS} = 600 V, V _{GS} = 0 V		-	-	50	μΑ
Zero Gate Voltage Drain Guirent	I _{DSS}	$V_{DS} = 480 \text{ V}$	$V_{\rm S} = 0 \ V_{\rm T} = 125 \ ^{\circ}{\rm C}$	-	-	250	μΑ
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 10 A ^b	-	0.35	0.42	Ω
Forward Transconductance	9 _{fs}	V_{DS}	V _{DS} = 50 V, I _D = 10 A		-	-	S
Dynamic							
Input Capacitance	C _{iss}		-	2700	-	- -	
Output Capacitance	C _{oss}	$V_{DS} = 25 \text{ V},$ f = 1.0 MHz, see fig. 5		-	240		-
Reverse Transfer Capacitance	C_{rss}			-	21		-
Output Capacitance	C _{oss}	$V_{GS} = 0 V$	V _{DS} = 1.0 V , f = 1.0 MHz	-	2950	-	pF
Output Capacitance		$V_{GS} = 0 V$	V _{DS} = 480 V , f = 1.0 MHz	-	67	-	
Effective Output Capacitance	Coss eff.	$V_{GS} = 0 V$	V _{DS} = 0 V to 480 V	-	120	-	
Total Gate Charge	Q_g	V _{GS} = 10 V I _D = 17 A, V _{DS} = 480 V	1 17 1 1/ 100 1/	-	-	99	
Gate-Source Charge	Q_{gs}		-	-	32	nC	
Gate-Drain Charge	Q _{gd}		see fig. 6 and 13	-	-	47	
Turn-On Delay Time	t _{d(on)}				25	-	
Rise Time	t _r	V _{DD} :	V _{DD} = 300 V, I _D = 17 A,		82	-	- ns
Turn-Off Delay Time	t _{d(off)}	$R_G = 7.5 \Omega$, $V_{GS} = 10 V$, see fig. 10^b		-	38	-	
Fall Time	t _f			-	32	-	
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	,	MOSFET symbol		-	17	
Pulsed Diode Forward Current ^a	I _{SM}	showing the integral reverse p - n junction diode		-	-	68	A
Body Diode Voltage	V _{SD}	$T_J = 25 ^{\circ}\text{C}, I_S = 17 \text{A}, V_{GS} = 0 \text{V}^{\text{b}}$		-	-	1.5	٧
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 17 A, dl/dt = 100 A/μs ^b		-	520	780	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	5620	8430	nC
Body Diode Reverse Recovery Time	t _{rr}	$T_J = 125 ^{\circ}\text{C}, \ I_F = 17 \text{A}, \ \text{dI/dt} = 100 \text{A/}\mu\text{s}^b$		-	580	870	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	6470	9700	nC
Forward Turn-On Time	t _{on}	Intrinsic to	ırn-on time is negligible (turn-	on is don	ninated by	L _S and I	 L _D)

- a. Repetitive rating, pulse width limited by max. junction temperature. b. Pulse width $\leq 300~\mu s;$ duty cycle $\leq 2~\%.$



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

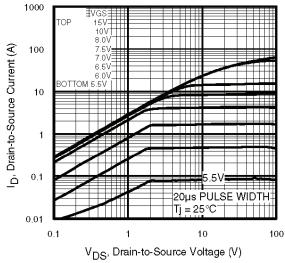


Fig. 1 - Typical Output Characteristics

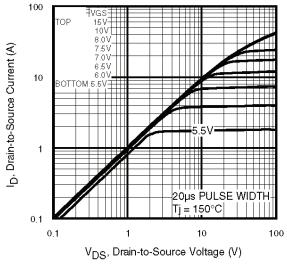


Fig. 2 - Typical Output Characteristics

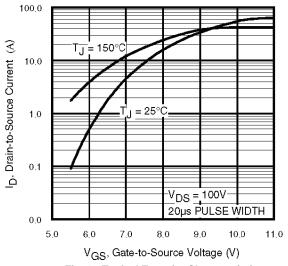


Fig. 3 - Typical Transfer Characteristics

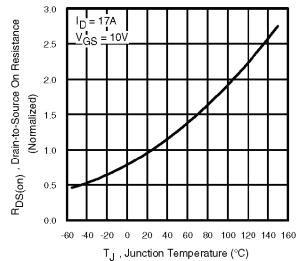


Fig. 4 - Normalized On-Resistance vs. Temperature

IRFB17N60K, SiHFB17N60K

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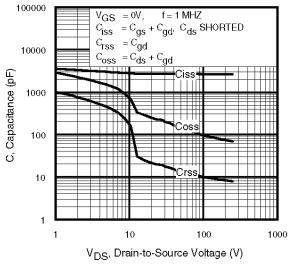


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

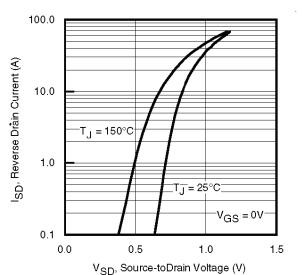


Fig. 7 - Typical Source-Drain Diode Forward Voltage

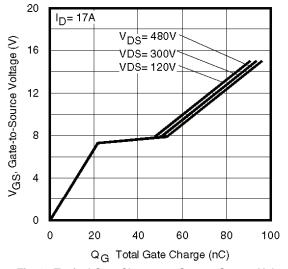


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

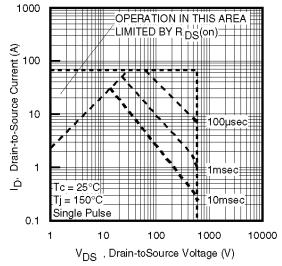


Fig. 8 - Maximum Safe Operating Area



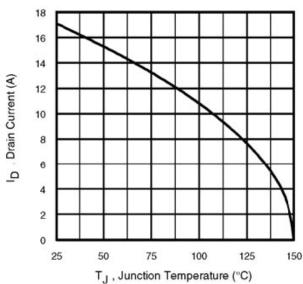


Fig. 9 - Maximum Drain Current vs. Case Temperature

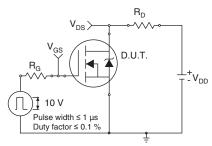


Fig. 10a - Switching Time Test Circuit

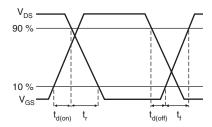


Fig. 10b - Switching Time Waveforms

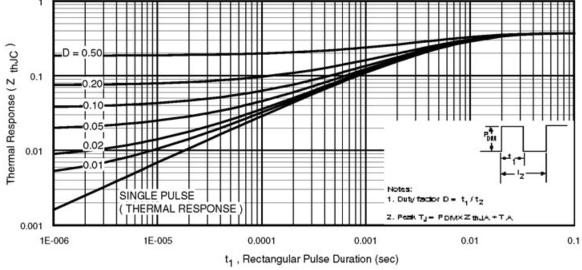


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

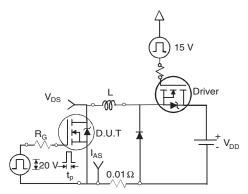


Fig. 12a - Unclamped Inductive Test Circuit

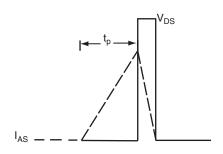


Fig. 12b - Unclamped Inductive Waveforms

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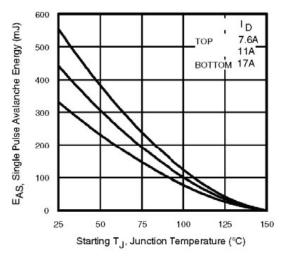


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

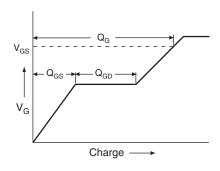


Fig. 13a - Basic Gate Charge Waveform

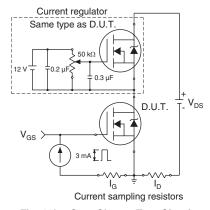
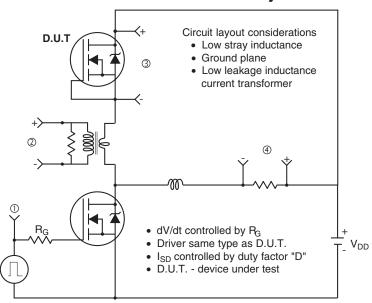
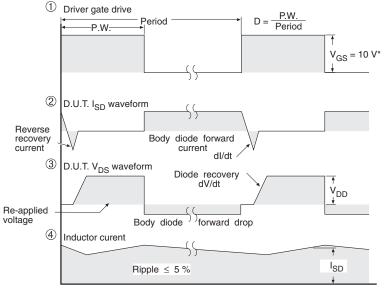


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit





* V_{GS} = 5 V for logic level devices

Fig. 14 - For N-Channel

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Revision: 18-Jul-08

Document Number: 91000 www.vishay.com